Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/608,761	WIEROWSKI, JAMES V.
Examiner	Art Unit
Le Nguyen	2174

SEARCHED				
Class	Subclass	Date	Examiner	
715	712	9/30/2007	LVN'	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	ь, USPAT: /712	9/30/2007	LVN	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
US-PGPub, USPAT: 715/712,734,738,739,805,838,850- 855,513; 701/201,208,210; 705/26,27	9/22/2007	LVN